Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/522,337	KAYAMA ET AL.
Examiner	Art Unit
Tran N. Nguyen	2834

Tran N. Nguyen

	SEAR	CHED	
Class	Subclass	Date	Examiner
310	81 254 407.1	5/24/	A
340	407.1	06	MA
	7.3	. , [
	7.6		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
<u> </u>		<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
<u> </u>		-		
		:		